

Figure 1 . 82527 Block Diagram

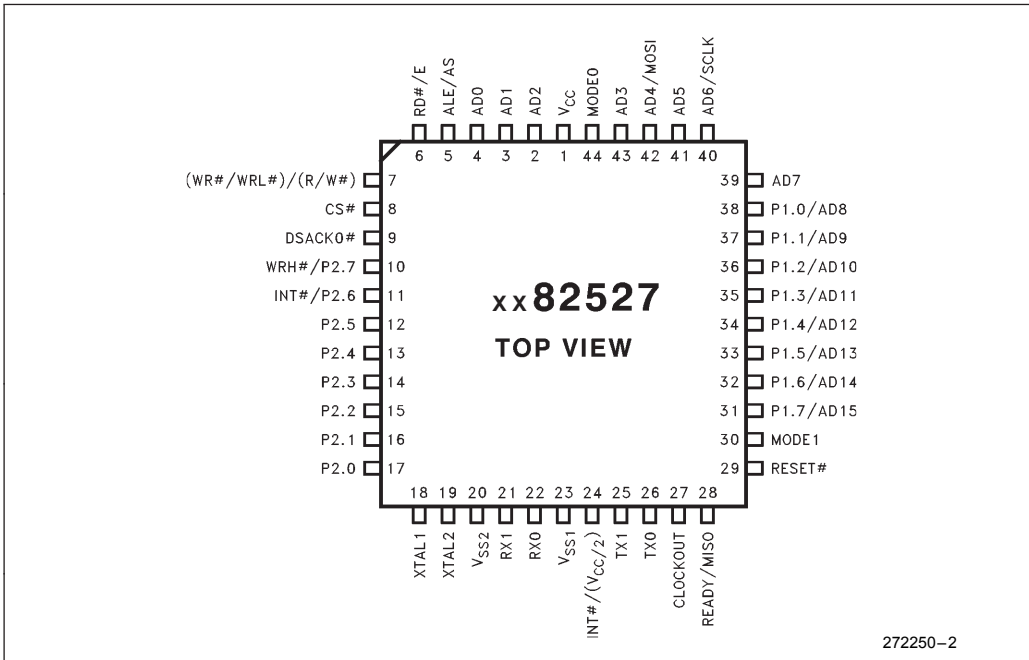


Figure 2 . 44-Pin PLCC Package

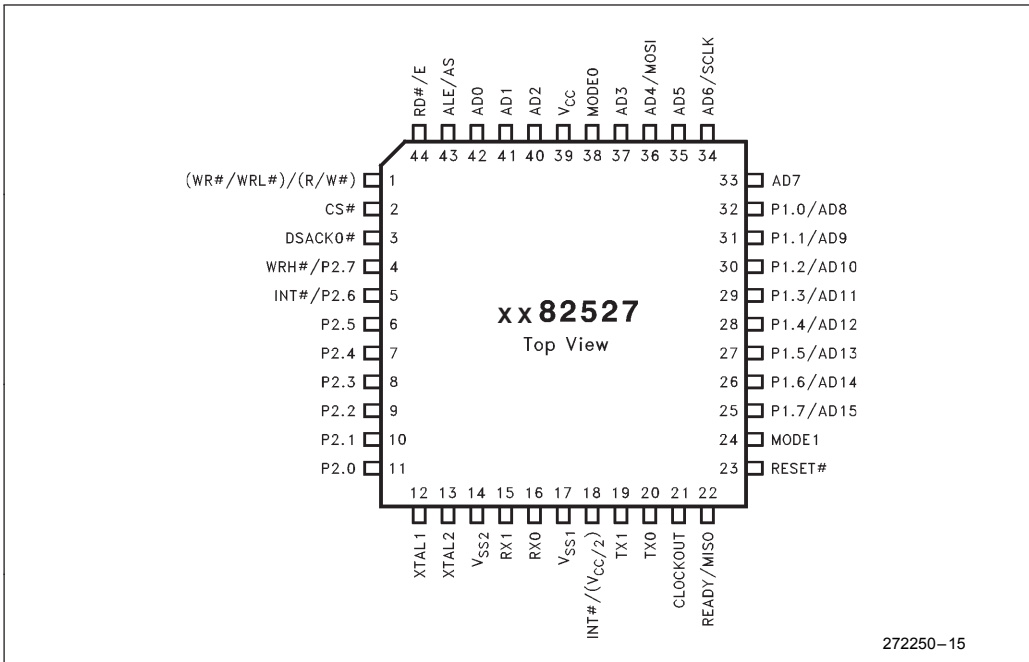


Figure 3. 44-Pin QFP Package

## PIN DESCRIPTION

The 82527 pins are described in this section. Table 1 presents the legend for interpreting the pin types.

Table 1. Pin Type Legend

Symbol	Description
I	Input only pin
O	Output only pin
I/O	Pin can be either input or output

## PIN DESCRIPTIONS

Pin Name	Pin Type	Pin Description
V <sub>SS1</sub>	Ground	GROUND connection must be connected externally to a V <sub>SS</sub> board plane. Provides digital ground.
V <sub>SS2</sub>	Ground	GROUND connection must be connected externally to a V <sub>SS</sub> board plane. Provides ground for analog comparator.
V <sub>CC</sub>	Power	POWER connection must be connected externally to +5V DC. Provides power for entire device.
XTAL1	I	Input for an external clock. XTAL1 (along with XTAL2) are the crystal connections to an internal oscillator.
XTAL2	O	Push-pull output from the internal oscillator. XTAL2 (along with XTAL1) are the crystal connections to an internal oscillator. If an external oscillator is used XTAL2 must be floated, or not be connected. XTAL2 must not be used as a clock output to drive other CPUs.
CLKOUT	O	Programmable clock output. This output may be used to drive the oscillator of the host microcontroller.
RESET#	I	Warm Reset: (V <sub>CC</sub> remains valid while RESET# is asserted), RESET# must be driven to a valid low level for 1 ms minimum. Cold Reset: (V <sub>CC</sub> is driven to a valid level while RESET# is asserted), RESET# must be driven low for 1 ms minimum measured from a valid V <sub>CC</sub> level. No falling edge on the reset pin is required during a cold reset event.
CS#	I	A low level on this pin enables CPU access to the 82527 device.
INT# (V <sub>CC/2</sub> )	O O	The interrupt pin is an open-drain output to the host microcontroller. V <sub>CC/2</sub> is the power supply for the ISO low speed physical layer. The function of this pin is determined by the MUX bit in the CPU Interface Register (Address 02H) as follows: MUX = 1: pin 24 (PLCC) = V <sub>CC/2</sub> , pin 11 = INT# MUX = 0: pin 24 (PLCC) = INT#
RX0 RX1	I I	Inputs from the CAN bus line(s) to the input comparator. A recessive level is read when RX0 > RX1. A dominant level is read when RX1 > RX0. When the CoBy bit (Bus Configuration register) is programmed as a ``1'', the input comparator is bypassed and RX0 is the CAN bus line input.
TX0 TX1	O O	Serial data push-pull output to the CAN bus line. During a recessive bit TX0 is high and TX1 is low. During a dominant bit TX0 is low and TX1 is high.

Pin Name	Pin Type	Pin Description																		
AD0/A0/ICP AD1/A1/CP AD2/A2/CSAS AD3/A3/STE AD4/A4/MOSI AD5/A5 AD6/A6/SCLK AD7/A7	I/O-I-I I/O-I-I I/O-I-I I/O-I I/O-I-I I/O-I I/O-I-I I/O-I	Address/Data bus in 8-bit multiplexed mode. Address bus in 8-bit non-multiplexed mode. Low byte of A/D bus in 16-bit multiplexed mode. In Serial Interface mode, the following pins have the following meaning: AD0: ICP Idle Clock Polarity AD1: CP Clock Phase AD2: CSAS Chip Select Active State AD3: STE Sync Transmit Enable AD6: SCLK Serial Clock Input AD4: MOSI Serial Data Input																		
AD8/D0/P1.0 AD9/D1/P1.1 AD10/D2/P1.2 AD11/D3/P1.3 AD12/D4/P1.4 AD13/D5/P1.5 AD14/D6/P1.6 AD15/D7/P1.7	I/O-O-I/O I/O-O-I/O I/O-O-I/O I/O-O-I/O I/O-O-I/O I/O-O-I/O I/O-O-I/O I/O-O-I/O	High byte of A/D bus in 16-bit multiplexed mode. Data bus in 8-bit non-multiplexed mode. Low speed I/O port. P1 pins in 8-bit multiplexed mode and serial mode. Port pins have weak pullups until the port is configured by writing to 9FH and AFH.																		
P2.0 P2.1 P2.2 P2.3 P2.4 P2.5 P2.6/INT # P2.7/WRH #	I/O I/O I/O I/O I/O I/O I/O-O I/O-I	P2 in all modes. P2.6 is INT # when MUX = 1 and is open-drain. P2.7 is WRH # in 16-bit multiplexed mode.																		
Mode0 Mode1	I I	These pins select one of the four parallel interfaces. These pins are weakly held low during reset. <table border="0"> <thead> <tr> <th>Mode1</th> <th>Mode0</th> <th></th> </tr> </thead> <tbody> <tr> <td>0</td> <td>0</td> <td>8-bit multiplexed Intel</td> </tr> <tr> <td>0</td> <td>0</td> <td>Serial Interface mode entered when RD# = 0, WR# = 0 upon reset.</td> </tr> <tr> <td>0</td> <td>1</td> <td>16-bit multiplexed Intel</td> </tr> <tr> <td>1</td> <td>0</td> <td>8-bit multiplexed non-Intel</td> </tr> <tr> <td>1</td> <td>1</td> <td>8-bit non-multiplexed</td> </tr> </tbody> </table>	Mode1	Mode0		0	0	8-bit multiplexed Intel	0	0	Serial Interface mode entered when RD# = 0, WR# = 0 upon reset.	0	1	16-bit multiplexed Intel	1	0	8-bit multiplexed non-Intel	1	1	8-bit non-multiplexed
Mode1	Mode0																			
0	0	8-bit multiplexed Intel																		
0	0	Serial Interface mode entered when RD# = 0, WR# = 0 upon reset.																		
0	1	16-bit multiplexed Intel																		
1	0	8-bit multiplexed non-Intel																		
1	1	8-bit non-multiplexed																		
ALE/AS	I-I	ALE used for Intel modes. AS used for non-Intel modes, except Mode 3 this pin must be tied high.																		
RD# E	I I	RD# used for Intel modes. E used for non-Intel modes, except Mode 3 Asynchronous this pin must be tied high.																		
WR#/WRL # R/W #	I I	WR# in 8-bit Intel mode and WRL# in 16-bit Intel mode. R/W # used for non-Intel modes.																		
READY MISO	O O	READY is an output to synchronize accesses from the host microcontroller to the 82527. READY is an open-drain output to the host microcontroller. MISO is the serial data output for the serial interface mode.																		
DSACK0#	O	DSACK0# is an open-drain output to synchronize accesses from the host microcontroller to the 82527.																		

## ELECTRICAL CHARACTERISTICS

NOTICE: This is a production data sheet. The specifications are subject to change without notice.

## ABSOLUTE MAXIMUM RATINGS\*

Storage Temperature.....  $-60^{\circ}\text{C}$  to  $+150^{\circ}\text{C}$   
 Voltage from Any Pin  
 to  $V_{SS}$ .....  $-0.5\text{V}$  to  $+7.0\text{V}$

*\*WARNING: Stressing the device beyond the "Absolute Maximum Ratings" may cause permanent damage. These are stress ratings only. Operation beyond the "Operating Conditions" is not recommended and extended exposure beyond the "Operating Conditions" may affect device reliability.*

Laboratory testing shows the 82527 will withstand up to 10 mA of injected current into both RX0 and RX1 pins for a total of 20 days without sustaining permanent damage. This high current condition may be the result of shorted signal lines. The 82527 will not function properly if the RX0/RX1 input voltage exceeds  $V_{CC} + 0.5\text{V}$ .

D.C. Characteristics  $V_{CC} = 5\text{V} \pm 10\%$ ;  $T_A = -40^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ 

Symbol	Parameter	Min	Max	Conditions
$V_{IL}$	Input Low Voltage (All except RX0, RX1, AD0 $\pm$ AD7 in Mode 3)	$-0.5\text{V}$	0.8V	
$V_{IL1}$	Input Low Voltage for AD0 $\pm$ AD7 in Mode 3	$-0.5\text{V}$	0.5V	
$V_{IL2}$	Input Low Voltage (RX0) for Comparator Bypass Mode		0.5V	
$V_{IL3}$	Input Low Voltage for Port 1 and Port 2 Pins Not Used for Interface to Host CPU		$0.3 V_{CC}$	
$V_{IH}$	Input High Voltage (All except RX0, RX1, RESET#)	3.0V	$V_{CC} + 0.5\text{V}$	
$V_{IH1}$	Input High Voltage (RESET#) Hysteresis on RESET#	3.0V 200 mV	$V_{CC} + 0.5\text{V}$	
$V_{IH2}$	Input High Voltage (RX0) for Comparator Bypass Mode	4.0V		
$V_{IH3}$	Input High Voltage for Port 1 and Port 2 Pins Not Used for Interface to Host CPU	$0.7 V_{CC}$		
$V_{OL}$	Output Low Voltage (All Outputs except TX0, TX1)		0.45V	$I_{OL} = 1.6\text{ mA}$
$V_{OH}$	Output High Voltage (All Outputs except TX0, TX1, CLOCKOUT)	$V_{CC} - 0.8\text{V}$		$I_{OH} = -200\ \mu\text{A}$
$V_{OHR1}$	Output High Voltage (CLOCKOUT)	$0.8 V_{CC}$		$I_{OH} = -80\ \mu\text{A}$
$I_{LK}$	Input Leakage Current		$\pm 10\ \mu\text{A}$	$V_{SS} < V_{IN} < V_{CC}$
$C_{IN}$	PIN Capacitance**		10 pF	$f_{XTAL} = 1\text{ KHz}$

**D.C. Characteristics**  $V_{CC} = 5V \pm 10\%$ ;  $T_A = -40^\circ\text{C}$  to  $+125^\circ\text{C}$ 

Symbol	Parameter	Min	Max	Conditions
$I_{CC}$	Supply Current <sup>(1)</sup>		50 mA	$f_{XTAL} = 16\text{ MHz}$
$I_{SLEEP}$	Sleep Current <sup>(1)</sup> with $V_{CC}/2$ Output Enabled, No Load with $V_{CC}/2$ Output Disabled		700 $\mu\text{A}$ 100 $\mu\text{A}$	
$I_{PD}$	Powerdown Current <sup>(1)</sup>		25 $\mu\text{A}$	XTAL1 Clocked

**NOTES:**

\*\*Typical value based on characterization data.

Port pins are weakly held after reset until the port configuration registers are written (9FH, AFH).

1. All pins are driven to  $V_{SS}$  or  $V_{CC}$  including RX0 and RX1.

**PHYSICAL LAYER SPECIFICATIONS** Load Condition: 100 pF

**D.C. Characteristics**  $V_{CC} = 5V \pm 10\%$ ;  $T_A = -40^\circ\text{C}$  to  $+125^\circ\text{C}$ 

RX0/RX1 and TX0/TX1	Min	Max	Conditions
Input Voltage	-0.5V	$V_{CC} + 0.5V$	
Common Mode Range	$V_{SS} + 1V$	$V_{CC} - 1V$	
Differential Input Threshold	$\pm 100\text{ mV}$		
Internal Delay 1: Sum of the Comparator Input Delay and the TX0/TX1 Output Driver Delay		60 ns	Load on TX0, TX1 = 100 pF, +100 mV to -100 mV RX0/RX1 differential
Internal Delay 2: Sum of the RX0 Pin Delay (if the Comparator is Bypassed) and the TX0/TX1 Output Driver Delay		50 ns	Load on TX0, TX1 = 100 pF
Source Current on Each TX0, TX1		-10 mA	$V_{OUT} = V_{CC} - 1.0V$
Sink Current on Each TX0, TX1		10 mA	$V_{OUT} = 1.0V$
Input Hysteresis for RX0/RX1		0V	
$V_{CC}/2$			
$V_{CC}/2$	2.38V	2.62V	$I_{OUT} \leq 75\ \mu\text{A}$ , $V_{CC} = 5V$

**CLOCKOUT SPECIFICATIONS**

Load Condition: 50 pF

Parameter	Min	Max
CLOCKOUT Frequency	XTAL/15	XTAL

**A.C. Characteristics for 8/16-Bit Multiplexed Intel Modes (Modes 0, 1)**

 Conditions:  $V_{CC} = 5V \pm 10\%$ ,  $V_{SS} = 0V$ ,  $T_A = -40^\circ C$  to  $+125^\circ C$ ,  $C_L = 100$  pF

Symbol	Parameter	Min	Max	Conditions
$1/t_{XTAL}$	Oscillator Frequency	8 MHz	16 MHz	
$1/t_{SCLK}$	System Clock Frequency	4 MHz	10 MHz	
$1/t_{MCLK}$	Memory Clock Frequency	2 MHz	8 MHz	
$t_{AVLL}$	Address Valid to ALE Low	7.5 ns		
$t_{LLAX}$	Address Hold after ALE Low	10 ns		
$t_{LHLL}$	ALE High Time	30 ns		
$t_{LLRL}$	ALE Low to RD# Low	20 ns		
$t_{CLLL}$	CS# Low to ALE Low	10 ns		
$t_{QVWH}$	Data Setup to WR# High	27 ns		
$t_{WHQX}$	Input Data Hold after WR# High	10 ns		
$t_{WLWH}$	WR# Pulse Width	30 ns		
$t_{WHLH}$	WR# High to Next ALE High	8 ns		
$t_{WHCH}$	WR# High to CS# High	0 ns		
$t_{RLRH}$	RD# Pulse Width This time is long enough to initiate a double read cycle by loading the High Speed Registers (04H, 05H), but is too short to READ from 04H and 05H (See $t_{RLDV}$ )	40 ns		
$t_{RLDV}$	RD# Low to Data Valid (Only for Registers 02H, 04H, 05H)	0 ns	55 ns	
$t_{RLDV1}$	RD# Low Data to Data Valid (for Registers except 02H, 04H, 05H) for Read Cycle without a Previous Write <sup>(1)</sup> for Read Cycle with a Previous Write <sup>(1)</sup>		1.5 $t_{MCLK} + 100$ ns 3.5 $t_{MCLK} + 100$ ns	
$t_{RHDZ}$	Data Float after RD# High	0 ns	45 ns	
$t_{CLYV}$	CS# Low to READY Setup Condition: Load Capacitance on the READY Output: 50 pF		32 ns 40 ns	$V_{OL} = 1.0V$ $V_{OL} = 0.45V$
$t_{WLYZ}$	WR# Low to READY Float for a Write Cycle if No Previous Write is Pending <sup>(2)</sup>		145 ns	
$t_{WHYZ}$	End of Last Write to READY Float for a Write Cycle if a Previous Write Cycle is Active <sup>(2)</sup>		2 $t_{MCLK} + 100$ ns	
$t_{RLYZ}$	RD# Low to READY Float (for registers except 02H, 04H, 05H) for Read Cycle without a Previous Write <sup>(1)</sup> for Read Cycle with a Previous Write <sup>(1)</sup>		2 $t_{MCLK} + 100$ ns 4 $t_{MCLK} + 100$ ns	



**A.C. Characteristics for 8/16-Bit Multiplexed Intel Modes (Modes 0, 1)**

Conditions:  $V_{CC} = 5V \pm 10\%$ ,  $V_{SS} = 0V$ ,  $T_A = -40^\circ C$  to  $+125^\circ C$ ,  $C_L = 100$  pF (Continued)

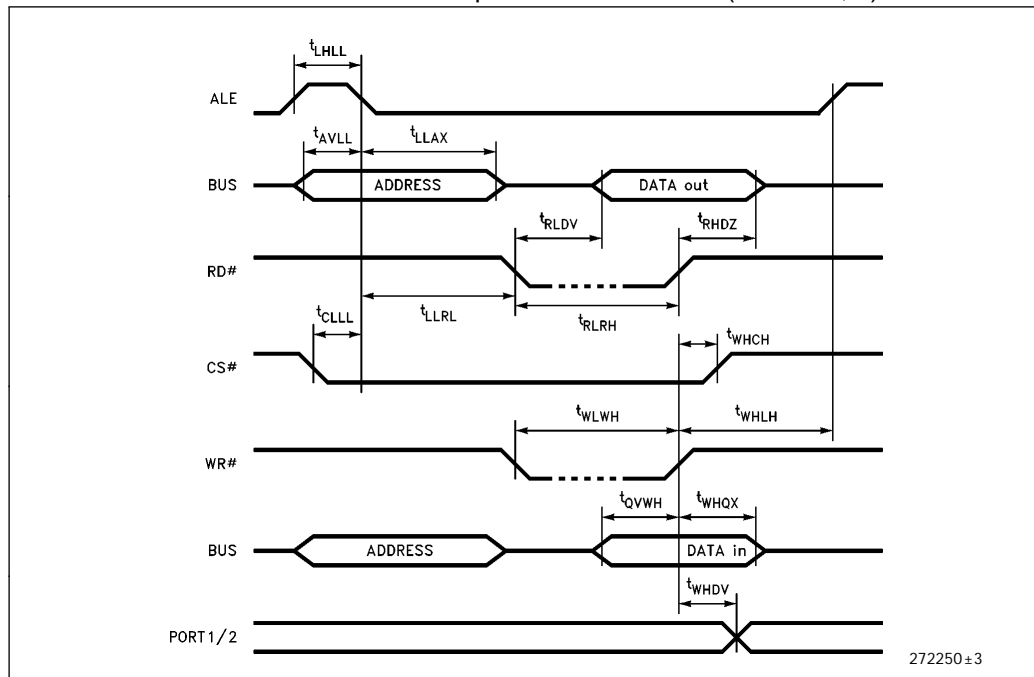
Symbol	Parameter	Min	Max	Conditions
$t_{WHDV}$	WR# High to Output Data Valid on Port 1/2	$t_{MCLK}$	$2 t_{MCLK} + 500$ ns	
$t_{COPO}$	CLKOUT Period	$(CD_V + 1) * t_{OSC}^{(3)}$		
$t_{CHCL}$	CLKOUT High Period	$(CD_V + 1) * \frac{1}{2} t_{OSC} - 10$	$(CD_V + 1) * \frac{1}{2} t_{OSC} + 15$	

**NOTES:**

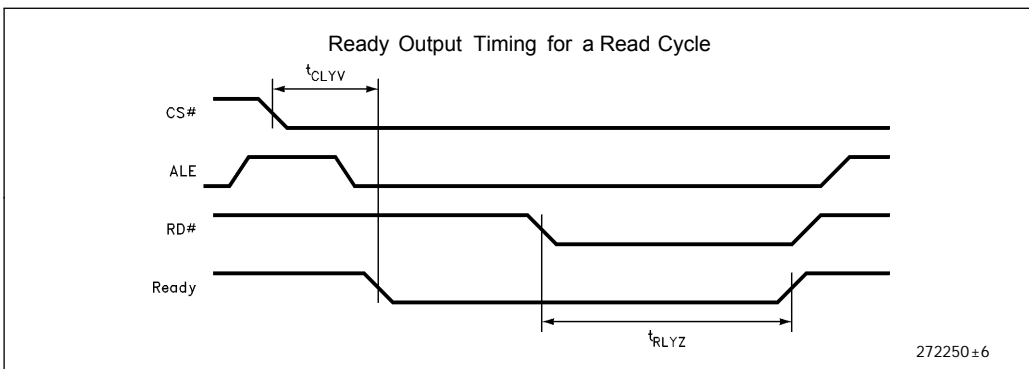
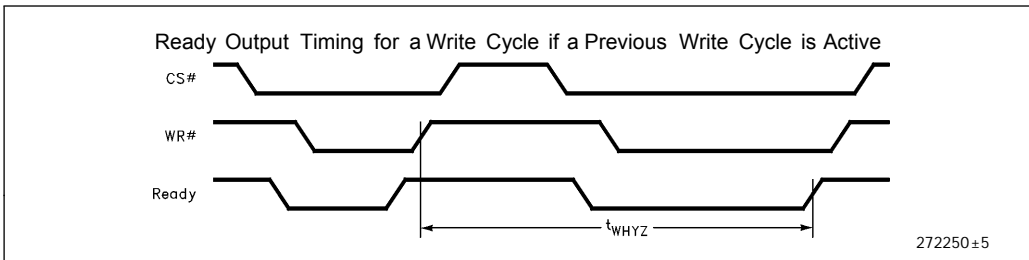
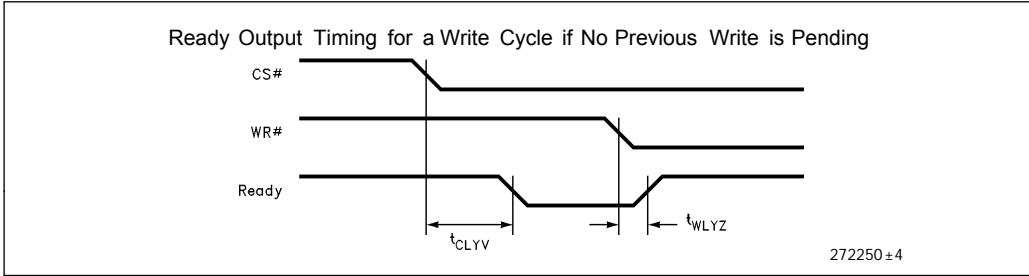
References to WR# also pertain to WRH#.

1. Definition of "read cycle without a previous write": The time between the rising edge of WR#/WRH# (for the previous write cycle) and the falling edge of RD# (for the current read cycle) is greater than  $2 t_{MCLK}$ .
2. Definition of "write cycle with a previous write": The time between the rising edge of WR#/WRH# (for the previous write cycle) and the rising edge of WR#/WRH# (for the current write cycle) is less than  $2 t_{MCLK}$ .
3. Definition of  $CD_V$  is the value loaded in the CLKOUT register representing the CLKOUT divisor.

**A.C. Characteristics for 8/16-Bit Multiplexed Intel Modes (Modes 0, 1)**



A.C. Characteristics for 8/16-Bit Multiplexed Intel Modes (Modes 0, 1)



**A.C. Characteristics for 8-Bit Multiplexed Non-Intel Mode (Mode 2)**

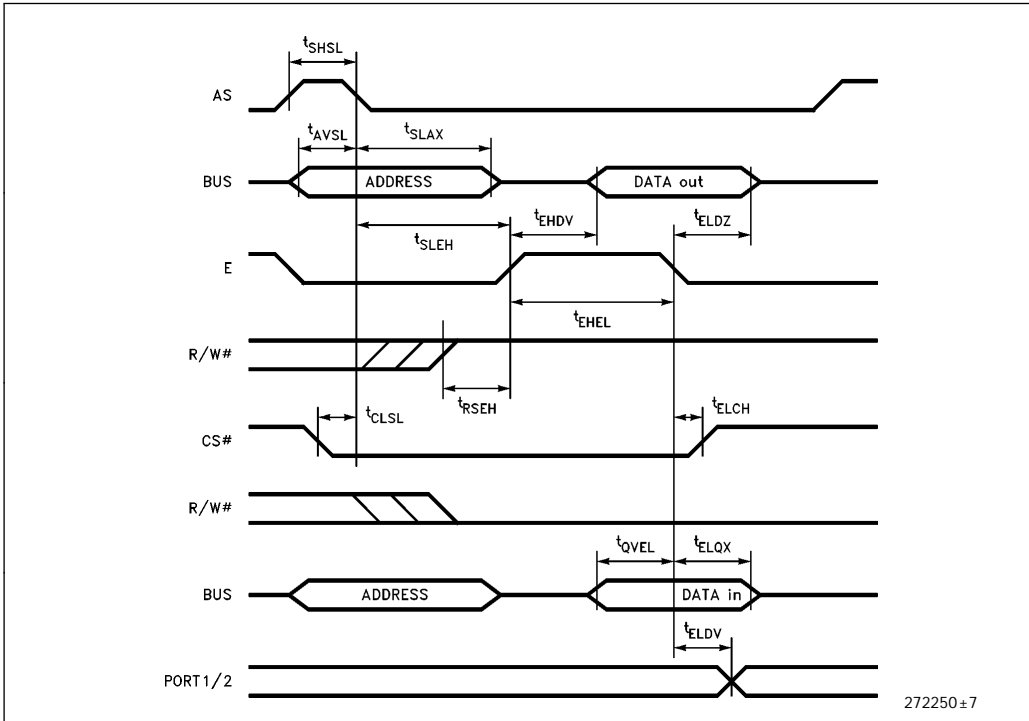
 Conditions:  $V_{CC} = 5V \pm 10\%$ ,  $V_{SS} = 0V$ ,  $T_A = -40^\circ C$  to  $+125^\circ C$ ,  $C_L = 100$  pF

Symbol	Parameter	Min	Max
1/t <sub>XTAL</sub>	Oscillator Frequency	8 MHz	16 MHz
1/t <sub>SCLK</sub>	System Clock Frequency	4 MHz	10 MHz
1/t <sub>MCLK</sub>	Memory Clock Frequency	2 MHz	8 MHz
t <sub>AVSL</sub>	Address Valid to AS Low	7.5 ns	
t <sub>SLAX</sub>	Address Hold after AS Low	10 ns	
t <sub>ELDZ</sub>	Data Float after E Low	0 ns	45 ns
t <sub>EHDV</sub>	E High to Data Valid for Registers 02H, 04H, 05H	0 ns	45 ns
	for Read Cycle without a Previous Write <sup>(1)</sup> for Read Cycle with a Previous Write (for Registers except for 02H, 04H, 05H)		1.5 t <sub>MCLK</sub> + 100 ns 3.5 t <sub>MCLK</sub> + 100 ns
t <sub>QVEL</sub>	Data Setup to E Low	30 ns	
t <sub>ELOX</sub>	Input Data Hold after E Low	20 ns	
t <sub>ELDV</sub>	E Low to Output Data Valid on Port 1/2	t <sub>MCLK</sub>	2 t <sub>MCLK</sub> + 500 ns
t <sub>EHEL</sub>	E High Time	45 ns	
t <sub>ELEL</sub>	End of Previous Write (Last E Low) to E Low for a Write Cycle	2 t <sub>MCLK</sub>	
t <sub>SHSL</sub>	AS High Time	30 ns	
t <sub>RSEH</sub>	Setup Time of R/W # to E High	30 ns	
t <sub>SLEH</sub>	AS Low to E High	20 ns	
t <sub>CLSL</sub>	CS# Low to AS Low	20 ns	
t <sub>ELCH</sub>	E Low to CS# High	0 ns	
t <sub>COPD</sub>	CLKOUT Period	$(CD_V + 1) * t_{OSC}^{(3)}$	
t <sub>CHCL</sub>	CLKOUT High Period	$(CD_V + 1) * \frac{1}{2} t_{OSC} - 10$	$(CD_V + 1) * \frac{1}{2} t_{OSC} + 15$

**NOTES:**

1. Definition of "Read Cycle without a Previous Write": The time between the falling edge of E (for the previous write cycle) and the rising edge of E (for the current read cycle) is greater than 2 t<sub>MCLK</sub>.
2. Definition of "Write Cycle with a Previous Write": The time between the falling edge of E (for the previous write cycle) and the falling edge of E (for the current write cycle) is less than 2 t<sub>MCLK</sub>.
3. Definition of CD<sub>V</sub> is the value loaded in the CLKOUT register representing the CLKOUT divisor.

A.C. Characteristics for 8-Bit Multiplexed Non-Intel Mode (Mode 2)



**A.C. Characteristics for 8-Bit Non-Multiplexed Asynchronous (Mode 3)**

 Conditions:  $V_{CC} = 5V \pm 10\%$ ,  $V_{SS} = 0V$ ,  $T_A = -40^\circ C$  to  $+125^\circ C$ ,  $C_L = 100$  pF

Symbol	Parameter	Min	Max
1/t <sub>XTAL</sub>	Oscillator Frequency	8 MHz	16 MHz
1/t <sub>SCLK</sub>	System Clock Frequency	4 MHz	10 MHz
1/t <sub>MCLK</sub>	Memory Clock Frequency	2 MHz	8 MHz
t <sub>AVCL</sub>	Address or R/W # Valid to CS# Low Setup	3 ns	
t <sub>CLDV</sub>	CS# Low to Data Valid for High Speed Registers (02H, 04H, 05H)	0 ns	55 ns
	For Low Speed Registers (Read Cycle without Previous Write) <sup>(1)</sup>	0 ns	1.5 t <sub>MCLK</sub> + 100 ns
	For Low Speed Registers (Read Cycle with Previous Write) <sup>(1)</sup>	0 ns	3.5 t <sub>MCLK</sub> + 100 ns
t <sub>KLDV</sub>	DSACK0# Low to Output Data Valid for High Speed Read Register		23 ns
	For Low Speed Read Register	<0 ns	
t <sub>CHDV</sub>	82527 Input Data Hold after CS# High	15 ns	
t <sub>CHDH</sub>	82527 Output Data Hold after CS# High	0 ns	
t <sub>CHDZ</sub>	CS# High to Output Data Float		35 ns
t <sub>CHKH<sub>1</sub></sub>	CS# High to DSACK0# = 2.4V <sup>(3)</sup>	0 ns	55 ns
t <sub>CHKH<sub>2</sub></sub>	CS# High to DSACK0# = 2.8V		150 ns
t <sub>CHKZ</sub>	CS# High to DSACK0# Float	0 ns	100 ns
t <sub>CHCL</sub>	CS# Width between Successive Cycles	25 ns	
t <sub>CHAI</sub>	CS# High to Address Invalid	7 ns	
t <sub>CHRI</sub>	CS# High to R/W # Invalid	5 ns	
t <sub>CLCH</sub>	CS# Width Low	65 ns	
t <sub>DVCH</sub>	CPU Write Data Valid to CS# High	20 ns	
t <sub>CLKL</sub>	CS# Low to DSACK0# Low for High Speed Registers and Low Speed Registers Write Access without Previous Write <sup>(2)</sup>	0 ns	67 ns
t <sub>CHKL</sub>	End of Previous Write (CS# High) to DSACK0# Low for a Write Cycle with a Previous Write <sup>(2)</sup>	0 ns	2 t <sub>MCLK</sub> + 145 ns
t <sub>COPD</sub>	CLKOUT Period	(CD <sub>V</sub> + 1) * t <sub>OSC</sub> <sup>(4)</sup>	
t <sub>CHCL</sub>	CLKOUT High Period	(CD <sub>V</sub> + 1) * 1/2 t <sub>OSC</sub> - 10	(CD <sub>V</sub> + 1) * 1/2 t <sub>OSC</sub> + 15

**NOTES:**

E and AS must be tied high in this mode.

 1. Definition of "Read Cycle without a Previous Write": The time between the rising edge of CS# (for the previous write cycle) and the falling edge of CS# (for the current read cycle) is greater than 2 t<sub>MCLK</sub>.

 2. Definition of "Write Cycle without a Previous Write": The time between the rising edge of CS# (for the previous write cycle) and the rising edge of CS# (for the current write cycle) is greater than 2 t<sub>MCLK</sub>.

3. An on-chip pullup will drive DSACK0# to approximately 2.4V. An external pullup is required to drive this signal to a higher voltage.

 4. Definition of CD<sub>V</sub> is the value loaded in the CLKOUT register representing the CLKOUT divisor.



















